

Structural, optical, and magnetic properties of Ar⁺, Mn⁺ and Ag⁺ ions implanted ZnO thin films: effect of implantation dose and stopping energy

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Supplementary Information

Section S1: Calculation of crystallite size “D” and lattice parameter “c”

The crystallite size “D” is estimated as follows

$$D = \frac{0.94\lambda}{\beta \cos\theta}$$

Where, λ is wavelength of radiation used. B is full width at half maximum for most intense peak, θ is Bragg angle.

The lattice parameters, c , of these films were calculated using the relation,

$$\frac{1}{d^2} = \frac{4(h^2 + hk + k^2)}{3a^2} + \frac{l^2}{c^2}$$

where (h,k,l) are the miller indices of a plane, d the interplanar spacing, and a and c are the lattice constants of unit cells. The lattice parameter, c , was derived from the (002) peak of the XRD patterns.

Table S1: Parameters used for simulation of RBS spectra of implanted films.

| Ions | Dose (ions/cm ²) | Thickness (Å) | Zn | O | M ⁺ (Ar/Mn/Ag) | Areal density of Zn (×10 ¹⁵ /cm ²) |
|-----------------|---------------------------------|------------------|----|---|------------------------------|--|
| No | Pristine | 1380 | 1 | 1 | | |
| Ar ⁺ | 1×10 ¹³ | 1205 | 1 | 1 | low | 4550 |
| | 1×10 ¹⁴ | 1164 | 1 | 1 | low | 4389 |
| | 1×10 ¹⁵ | 1156 | 1 | 1 | 0.01 | 4360 |
| | 2×10 ¹⁶ | 1101 | 1 | 1 | 0.04 | 4144 |
| | | | | | | |
| Mn ⁺ | 1×10 ¹³ | 1114 | 1 | 1 | overlap | 4215 |
| | 1×10 ¹⁴ | 1151 | 1 | 1 | overlap | 4361 |
| | 1×10 ¹⁵ | 1159 | 1 | 1 | overlap | 4392 |
| | 2×10 ¹⁶ | 1106 | 1 | 1 | overlap | 4185 |
| Ag ⁺ | 1×10 ¹³ | 1161 | 1 | 1 | low | 4399 |
| | 1×10 ¹⁴ | 1172 | 1 | 1 | low | 4444 |
| | 1×10 ¹⁵ | 1159 | 1 | 1 | 0.001 | 4389 |
| | 2×10 ¹⁶ | 1000 | 1 | 1 | 0.002 | 3776 |

Table S2: Main edge energy and spectral features in Zn *K*-edge NEXAFS spectra.

| Ions | Dose (ions/cm ²) | Main Edge Energy (eV) | a ₁ | b ₁ | c ₁ |
|-----------------|---------------------------------|--------------------------|----------------|----------------|----------------|
| Ar ⁺ | Pristine | 9659.8 | 9667.8 | 9679.0 | 9713.8 |
| | 1×10 ¹³ | 9659.9 | 9668.2 | 9679.7 | 9712.9 |
| | 1×10 ¹⁴ | 9659.8 | 9667.8 | 9679.4 | 9713.0 |
| | 1×10 ¹⁵ | 9659.9 | 9667.8 | 9679.4 | 9713.8 |
| | 2×10 ¹⁶ | 9659.8 | 9668.2 | 9679.4 | 9713.8 |
| Mn ⁺ | 1×10 ¹³ | 9660.0 | 9667.8 | 9679.8 | 9713.8 |
| | 1×10 ¹⁴ | 9659.9 | 9667.8 | 9679.8 | 9713.0 |
| | 1×10 ¹⁵ | 9659.9 | 9667.8 | 9679.4 | 9713.0 |
| | 2×10 ¹⁶ | 9659.9 | 9667.8 | 9679.8 | 9713.8 |
| Ag ⁺ | 1×10 ¹³ | 9659.8 | 9667.8 | 9679.4 | 9713.0 |
| | 1×10 ¹⁴ | 9659.8 | 9667.8 | 9679.4 | 9713.0 |
| | 1×10 ¹⁵ | 9660.0 | 9668.1 | 9679.8 | 9713.8 |
| | 2×10 ¹⁶ | 9659.8 | 9667.8 | 9679.4 | 9713.8 |

Table S3: Simulated parameters from EXAFS spectra for Ar⁺ implanted ZnO films. N is coordination number, R is bonding length, and σ² is Debye-Waller factor.

| Path | Parameters | Pristine | 1×10 ¹³ (ions/cm ²) | 1×10 ¹⁴ (ions/cm ²) | 1×10 ¹⁵ (ions/cm ²) | 2×10 ¹⁶ (ions/cm ²) |
|-----------------------|----------------------------------|-------------|---|---|---|---|
| Zn-O (I) | N | 4.2±0.9 | 3.9±0.4 | 4.0±0.5 | 3.9±0.4 | 3.8±0.4 |
| | R (Å) | 1.97±0.01 | 1.98±0.03 | 1.98±0.04 | 1.97±0.03 | 1.97±0.03 |
| | σ ² (Å ²) | 0.006±0.004 | 0.004 | 0.005 | 0.004 | 0.004 |
| Zn-Zn (I) | N | 4.9±1.5 | 5.4±1.1 | 5.6±1.3 | 5.2±1.1 | 4.9±1.1 |
| | R (Å) | 3.14±0.02 | 3.30±0.001 | 3.3±0.11 | 3.29±0.10 | 3.31±0.12 |
| | σ ² (Å ²) | 0.001 | 0.001 | 0.001 | 0.001 | 0.001 |
| Zn-Zn (II) | N | 6.0±1.5 | 4.9±1.2 | 5.2±1.4 | 4.7±1.2 | 5.5±1.2 |
| | R (Å) | 3.29±0.02 | 3.15±0.005 | 3.15±0.004 | 3.15±0.003 | 3.16±0.01 |
| | σ ² (Å ²) | 0.001 | 0.001 | 0.001 | 0.001 | 0.002 |
| Zn-O (II) | N | 8.2±2.4 | 8.9±2.5 | 8.4±2.9 | 8.6±2.6 | 7.8±2.3 |
| | R (Å) | 3.78±0.03 | 3.79±0.05 | 3.79±0.05 | 3.78±0.04 | 3.79±0.05 |
| | σ ² (Å ²) | 0.001 | 0.003 | 0.002 | 0.003 | 0.003 |
| | ε _o (eV) | 5.2 | 6.0 | 6.0 | 6.0 | 6.0 |
| | R-factor | 0.05 | 0.04 | 0.05 | 0.04 | 0.03 |

Table S4: Simulated parameters from EXAFS spectra for Mn⁺ implanted ZnO films.

| Path | Parameters | Pristine | 1×10^{13} (ions/cm ²) | 1×10^{14} (ions/cm ²) | 1×10^{15} (ions/cm ²) | 2×10^{16} (ions/cm ²) |
|-------------------------------------|------------------------------|-----------------|---|---|---|---|
| Zn-O (I) | N | 4.2 ± 0.9 | 4.1 ± 0.5 | 3.9 ± 0.5 | 3.9 ± 0.5 | 3.7 ± 0.5 |
| | R (Å) | 1.97 ± 0.01 | 1.98 ± 0.04 | 1.98 ± 0.04 | 1.98 ± 0.04 | 1.99 ± 0.04 |
| | σ^2 (Å ²) | 0.006 ± 0.004 | 0.005 | 0.004 | 0.004 | 0.004 |
| Zn-Zn (I) | N | 4.9 ± 1.5 | 5.7 ± 1.2 | 5.8 ± 1.3 | 5.8 ± 1.3 | 5.8 ± 1.3 |
| | R (Å) | 3.14 ± 0.02 | 3.31 ± 0.011 | 3.3 ± 0.11 | 3.31 ± 0.12 | 3.2 ± 0.12 |
| | σ^2 (Å ²) | 0.001 | 0.001 | 0.001 | 0.001 | 0.001 |
| Zn-Zn (II) | N | 6.0 ± 1.5 | 5.7 ± 1.4 | 5.7 ± 1.4 | 5.6 ± 1.3 | 5.4 ± 1.3 |
| | R (Å) | 3.29 ± 0.02 | 3.16 ± 0.01 | 3.15 ± 0.004 | 3.16 ± 0.01 | 3.16 ± 0.01 |
| | σ^2 (Å ²) | 0.001 | 0.002 | 0.002 | 0.001 | 0.002 |
| Zn-O (II) | N | 8.2 ± 2.4 | 8.5 ± 2.5 | 7.7 ± 2.5 | 8.4 ± 2.7 | 8.4 ± 2.9 |
| | R (Å) | 3.78 ± 0.03 | 3.80 ± 0.06 | 3.80 ± 0.06 | 3.80 ± 0.06 | 3.82 ± 0.08 |
| | σ^2 (Å ²) | 0.001 | 0.002 | 0.001 | 0.003 | 0.003 |
| ϵ_o (eV) | | 5.2 | 6.0 | 6.0 | 6.0 | 6.0 |
| R-factor | | 0.05 | 0.04 | 0.05 | 0.05 | 0.05 |

Table S5: Simulated parameters from EXAFS spectra for Ag⁺ implanted ZnO films.

| Path | Parameters | Pristine | 1×10^{13} (ions/cm ²) | 1×10^{14} (ions/cm ²) | 1×10^{15} (ions/cm ²) | 2×10^{16} (ions/cm ²) |
|-------------------------------------|------------------------------|-----------------|---|---|---|---|
| Zn-O (I) | N | 4.2 ± 0.9 | 4.0 ± 0.9 | 3.9 ± 0.5 | 3.7 ± 0.5 | 3.5 ± 0.4 |
| | R (Å) | 1.97 ± 0.01 | 1.98 ± 0.04 | 1.98 ± 0.04 | 2.00 ± 0.06 | 1.98 ± 0.04 |
| | σ^2 (Å ²) | 0.006 ± 0.004 | 0.004 | 0.004 | 0.004 | 0.003 |
| Zn-Zn (I) | N | 4.9 ± 1.5 | 6.0 ± 1.3 | 6.1 ± 1.3 | 6.2 ± 1.2 | 6.0 ± 1.2 |
| | R (Å) | 3.14 ± 0.02 | 3.31 ± 0.12 | 3.3 ± 0.11 | 3.34 ± 0.15 | 3.32 ± 0.13 |
| | σ^2 (Å ²) | 0.001 | 0.001 | 0.001 | 0.001 | 0.001 |
| Zn-Zn (II) | N | 6.0 ± 1.5 | 6.0 ± 1.4 | 5.8 ± 1.4 | 6.1 ± 1.2 | 6.1 ± 1.3 |
| | R (Å) | 3.29 ± 0.02 | 3.16 ± 0.01 | 3.16 ± 0.008 | 3.19 ± 0.04 | 3.17 ± 0.02 |
| | σ^2 (Å ²) | 0.001 | 0.002 | 0.002 | 0.001 | 0.002 |
| Zn-O (II) | N | 8.2 ± 2.4 | 7.5 ± 2.4 | 7.7 ± 2.4 | 9.2 ± 2.7 | 6.6 ± 2.3 |
| | R (Å) | 3.78 ± 0.03 | 3.81 ± 0.07 | 3.80 ± 0.06 | 3.86 ± 0.12 | 3.82 ± 0.08 |
| | σ^2 (Å ²) | 0.001 | 0.001 | 0.001 | 0.003 | 0.001 |
| ϵ_0 (eV) | | 5.2 | 6.0 | 5.6 | 6.1 | 7.1 |
| R-factor | | 0.05 | 0.03 | 0.05 | 0.05 | 0.04 |

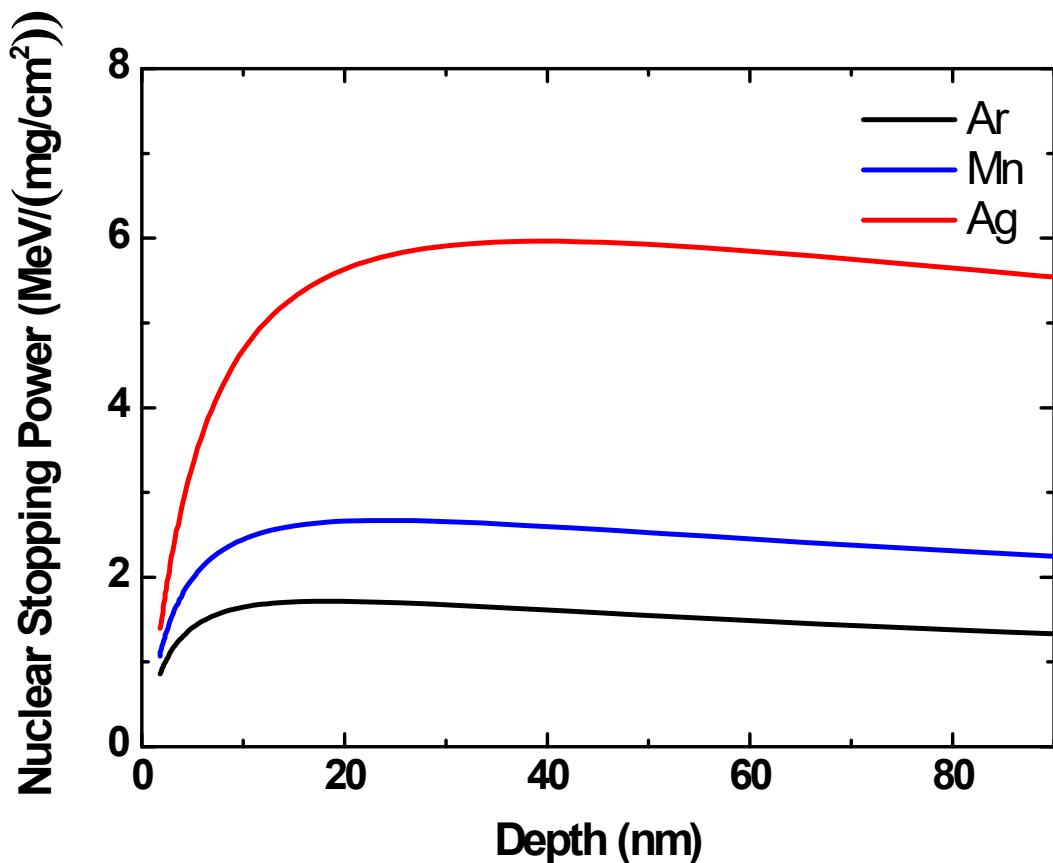


Figure S1: Energy transferred to the ZnO lattice during the implantation using Ar⁺, Mn⁺ and Ag⁺ ions.

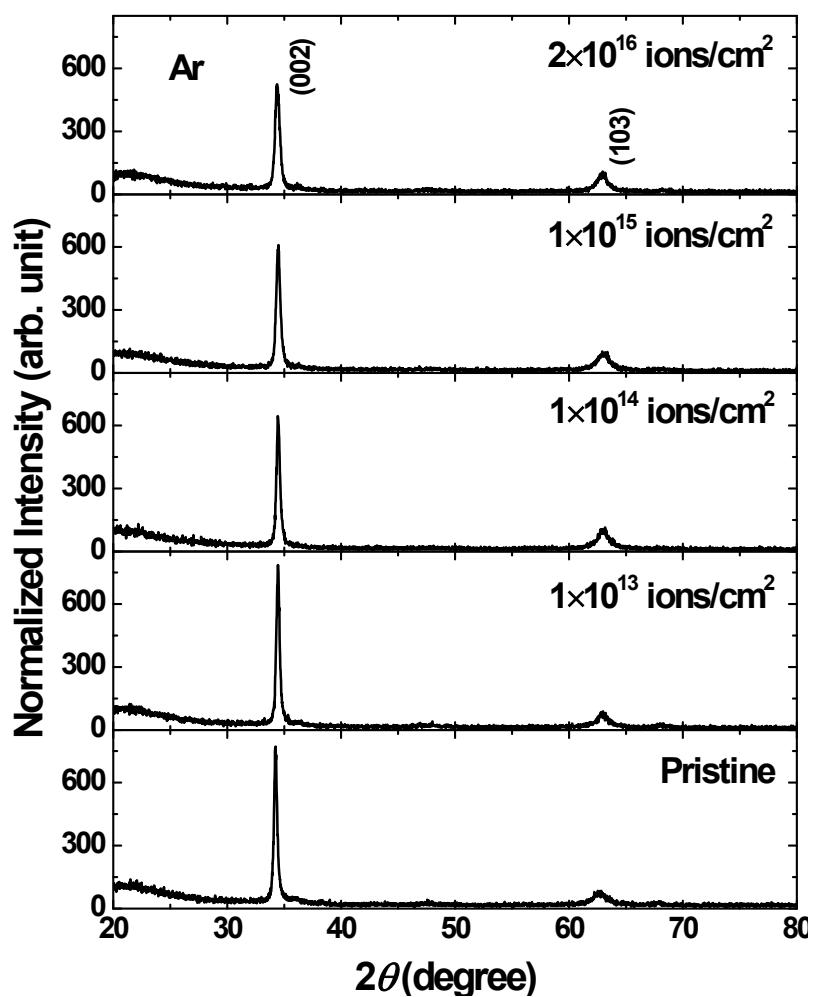


Figure S2: XRD patterns of the Ar⁺ implanted ZnO at different doses.

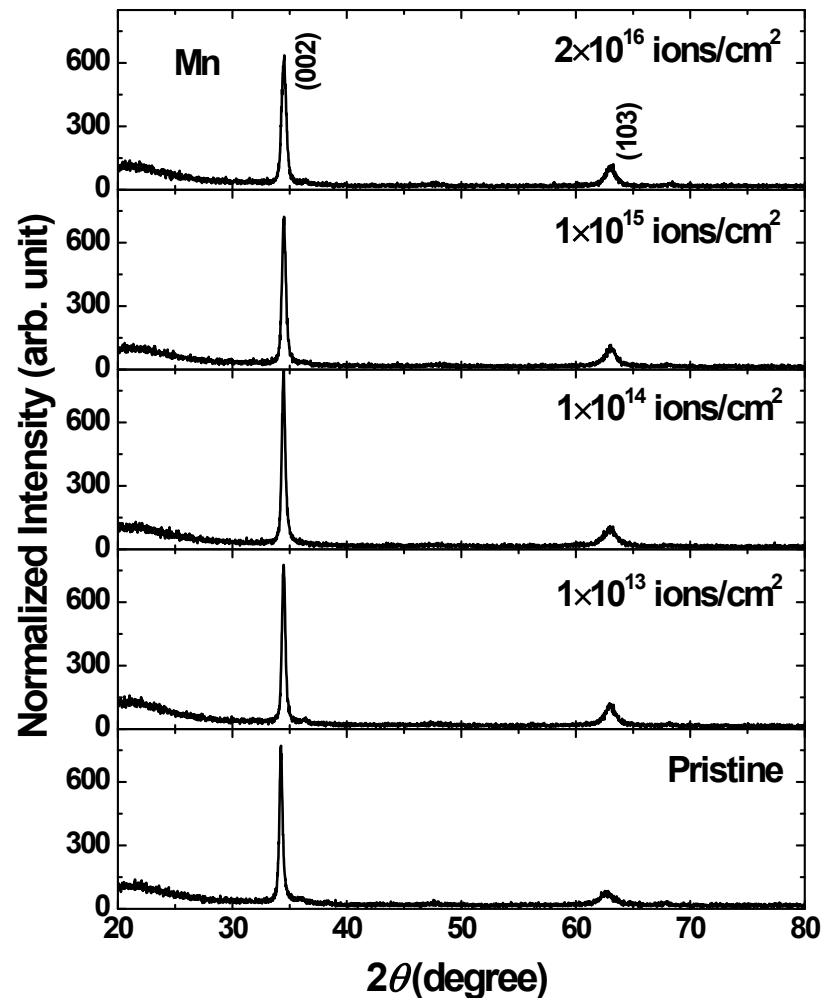


Figure S3: XRD patterns of the Mn⁺ implanted ZnO at different doses.

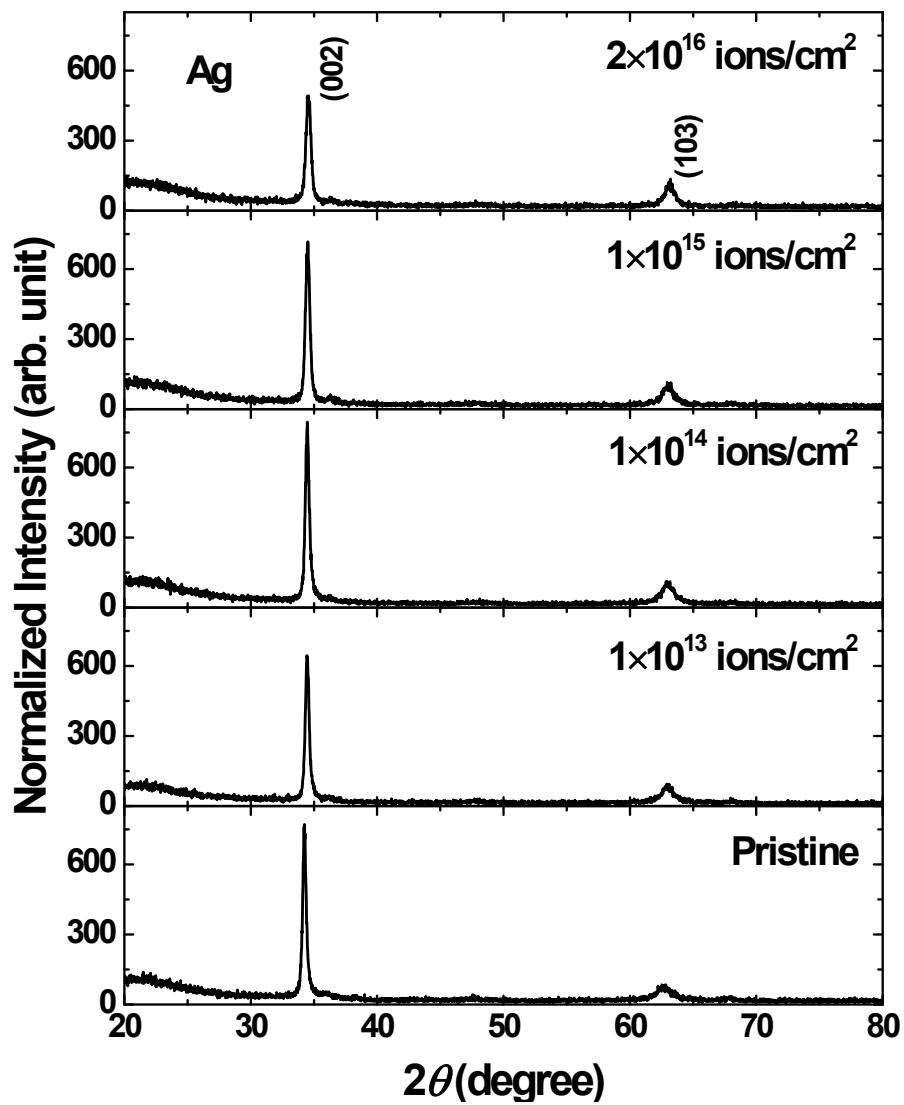


Figure S4: XRD patterns of the Ag^+ implanted ZnO at different doses.

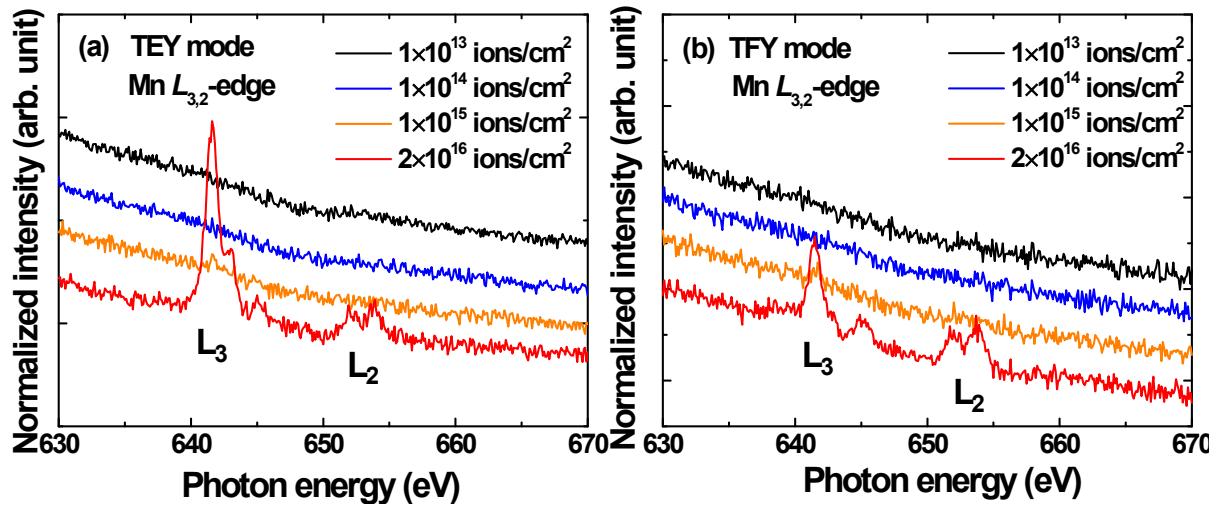


Figure S5: NEXAFS spectra at the Mn $L_{3,2}$ -edge of Mn doped ZnO thin films. (a) TEY mode (b) TFY mode.

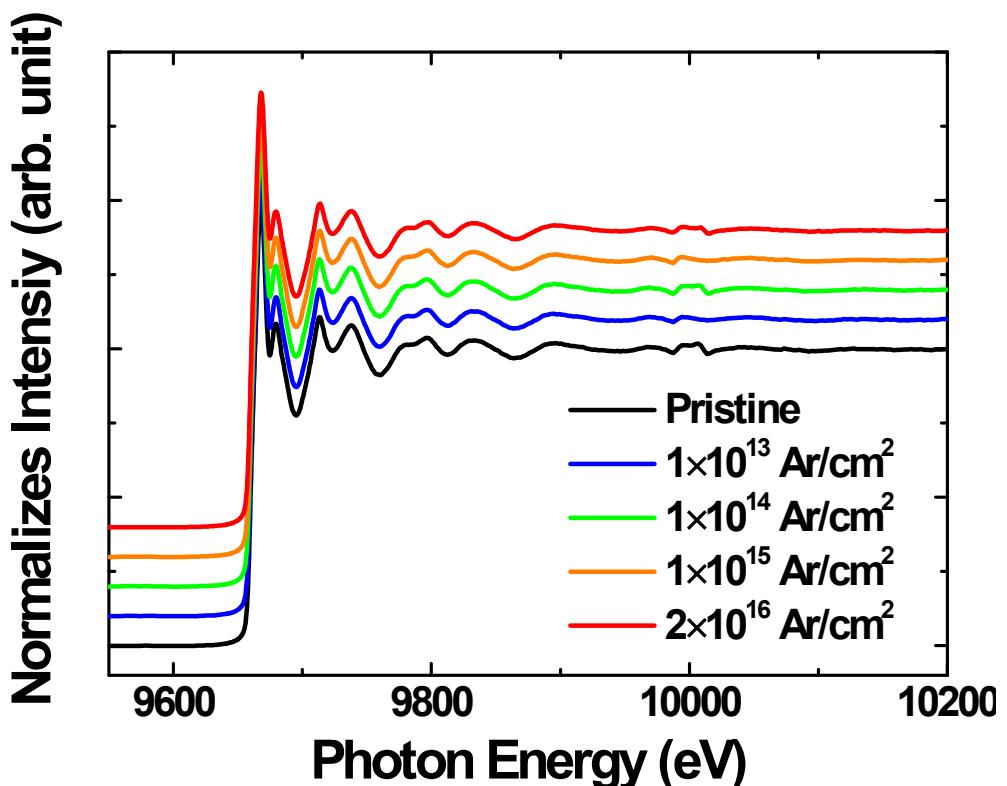


Figure S6: k -weight EXAFS spectra for Ar-implanted ZnO films at various doses.

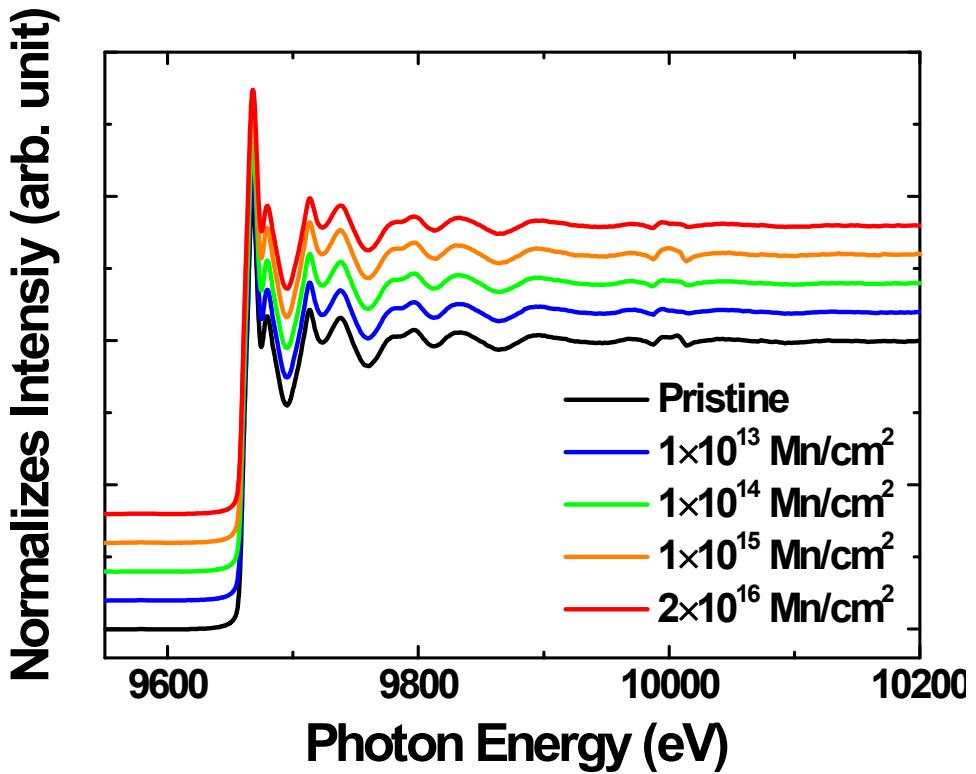


Figure S7: k -weight EXAFS spectra for Mn-implanted ZnO films at various doses.

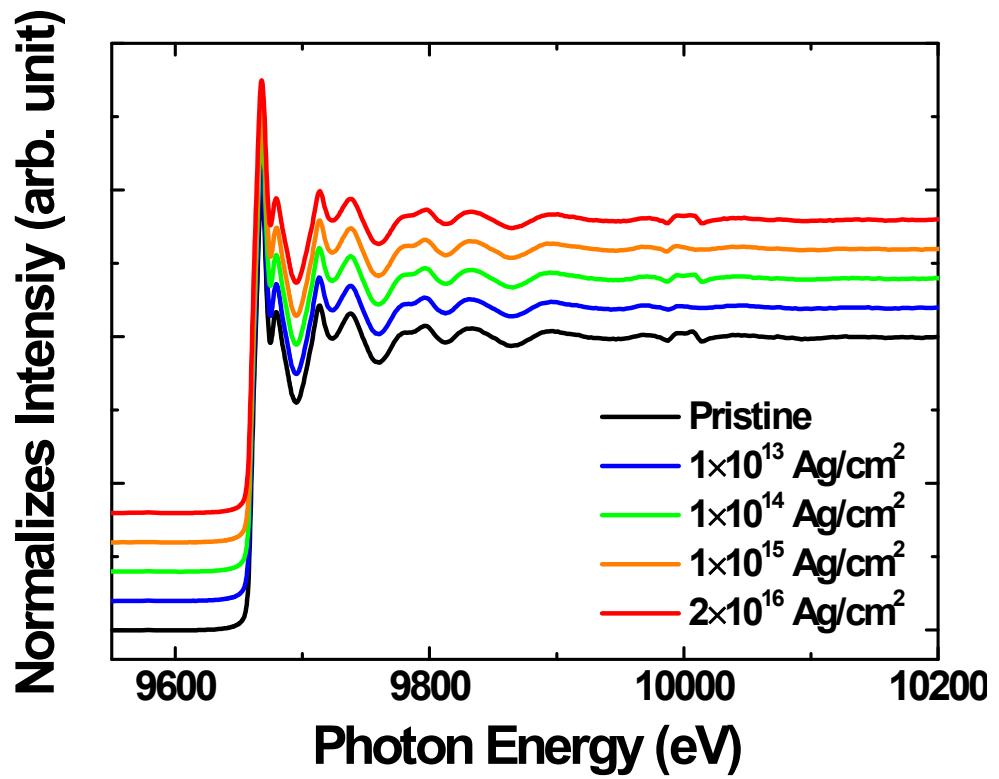


Figure S8: k -weight EXAFS spectra for Ag-implanted ZnO films at various doses.

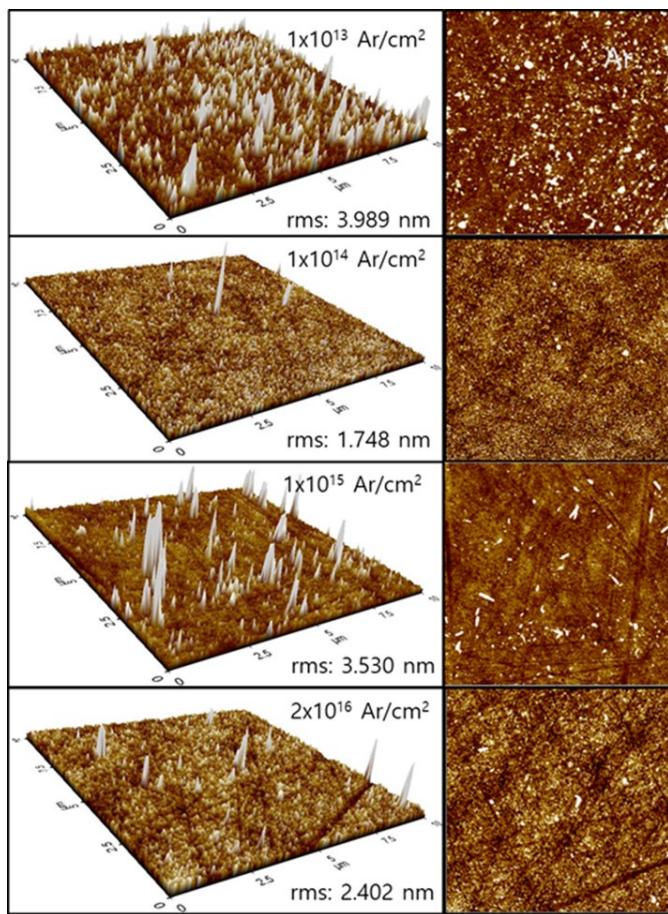


Figure S9: AFM images of the Ar-implanted ZnO at different doses.

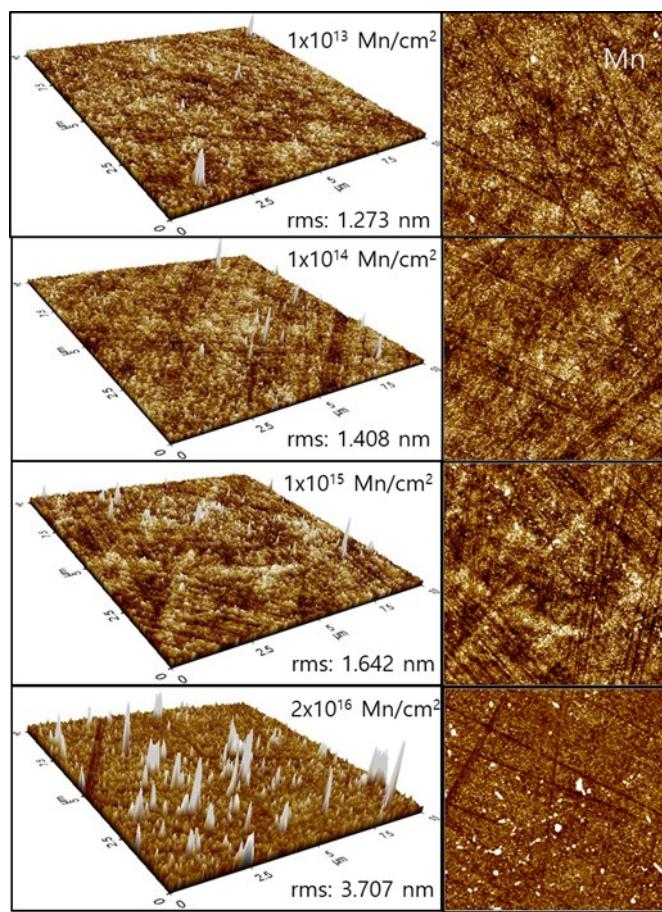


Figure S10: AFM images of the Mn-implanted ZnO at different doses.

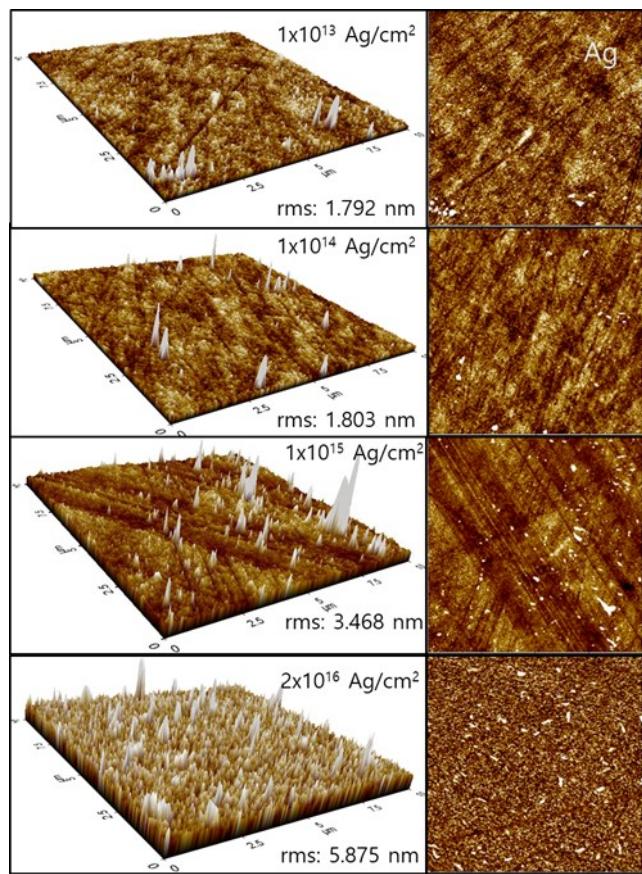


Figure S11: AFM images of the Ag-implanted ZnO at different doses.

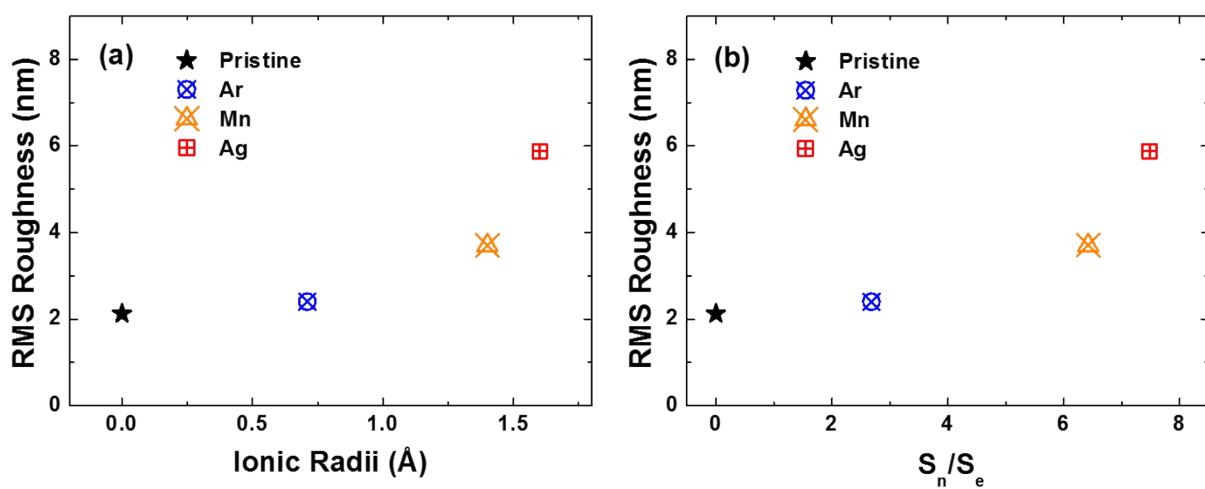


Figure S12: RMS roughness as a function of (a) ionic radii and (b) S_n/S_e .

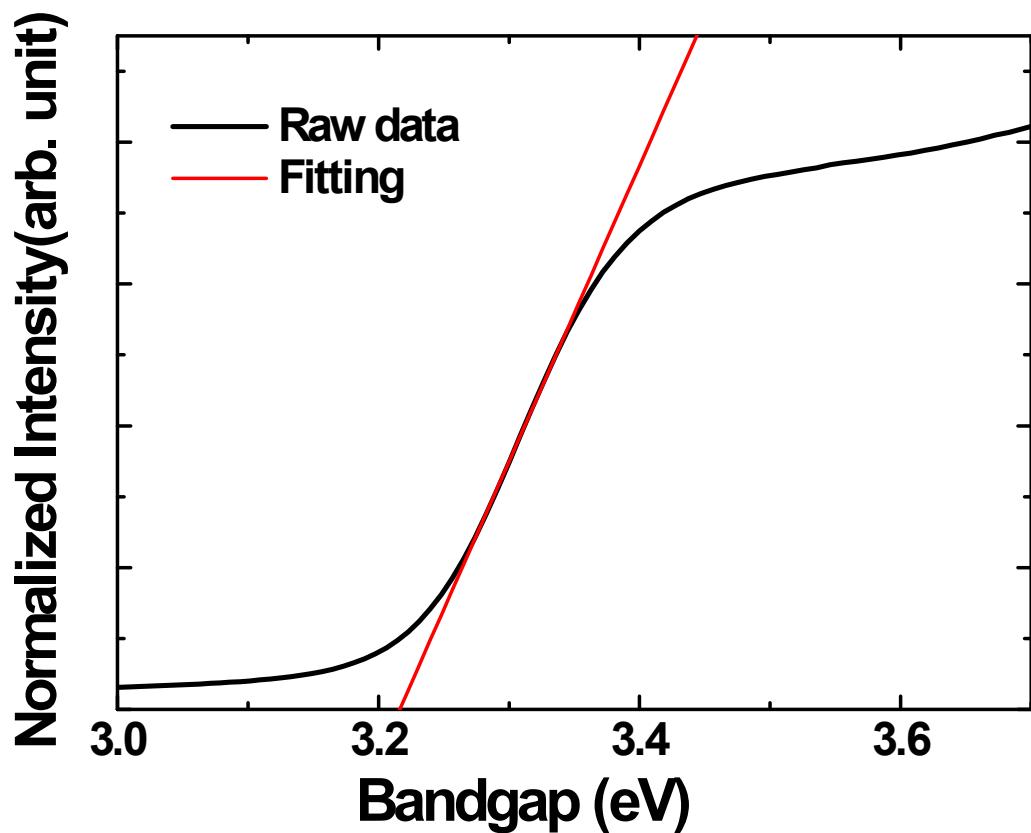


Figure S13: Estimation of optical bandgap from Tauc's plot for a representative film.

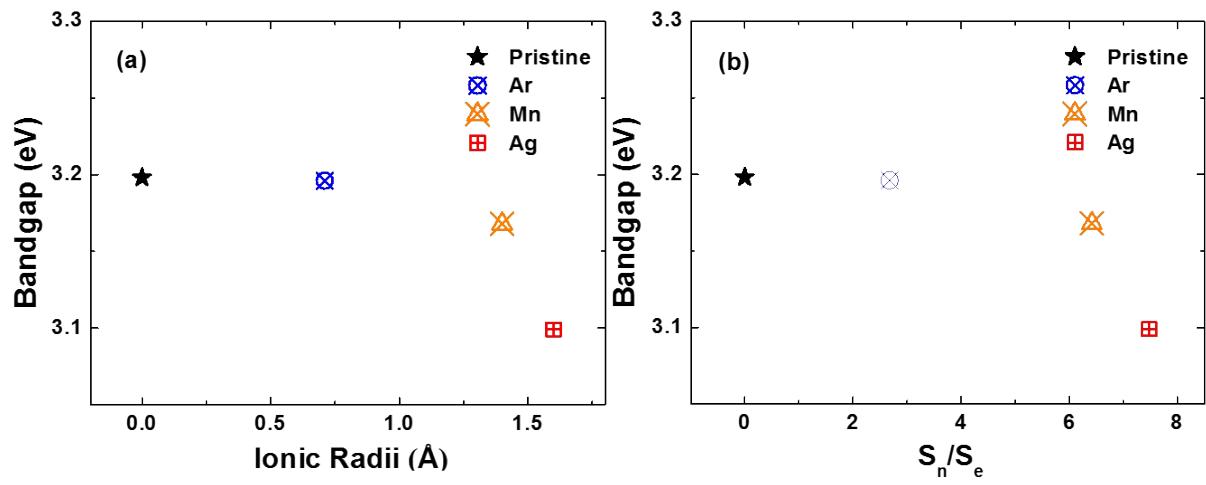


Figure S14: Optical band-gap as a function of (a) ionic radii and (b) S_n/S_e corresponding to various implanted ions.

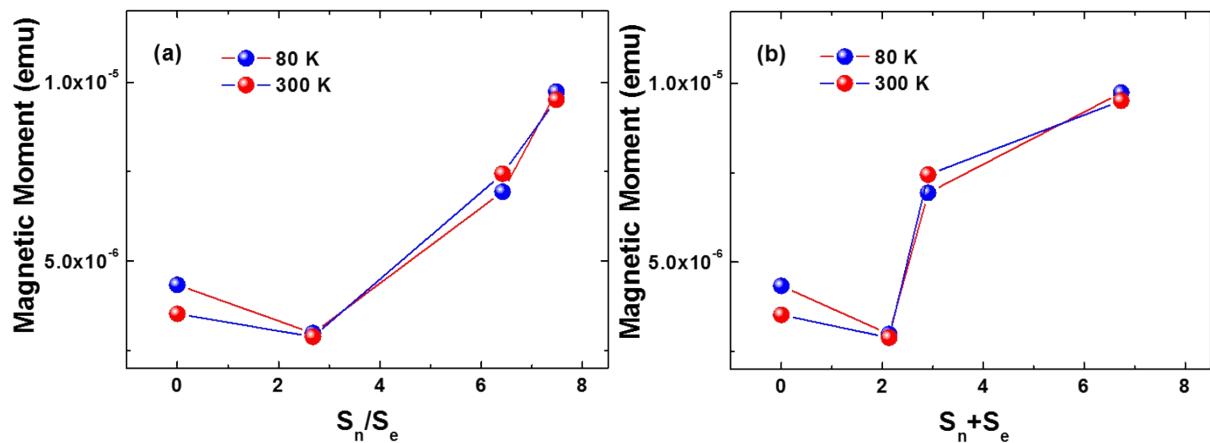


Figure S15: Magnetic moment as a function of (a) ionic radii and (b) S_n/S_e corresponding to various implanted ions.

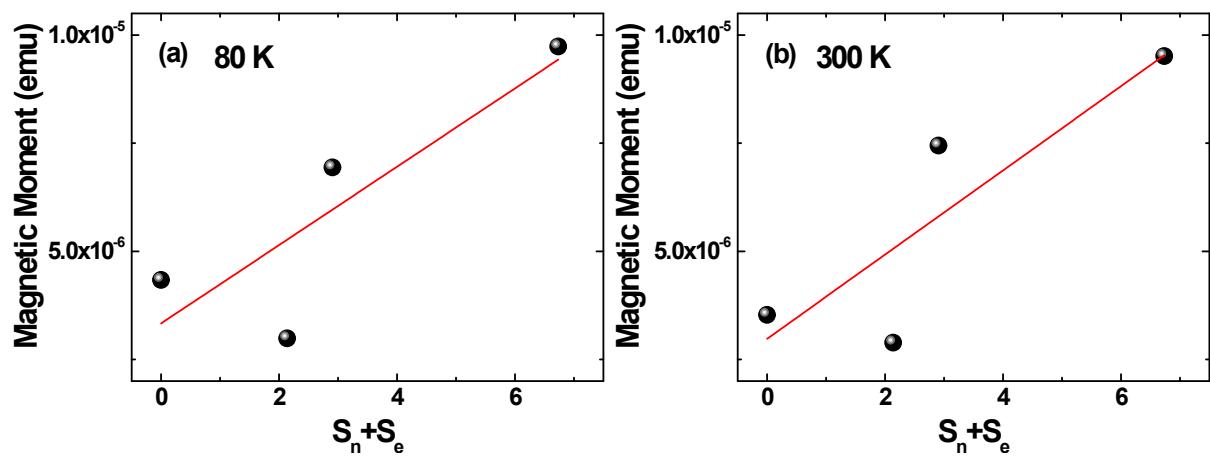


Figure S16: Magnetic moment as a function of $S_n + S_e$ corresponding to various implanted ions at (a) 80 K and (b) 300 K.

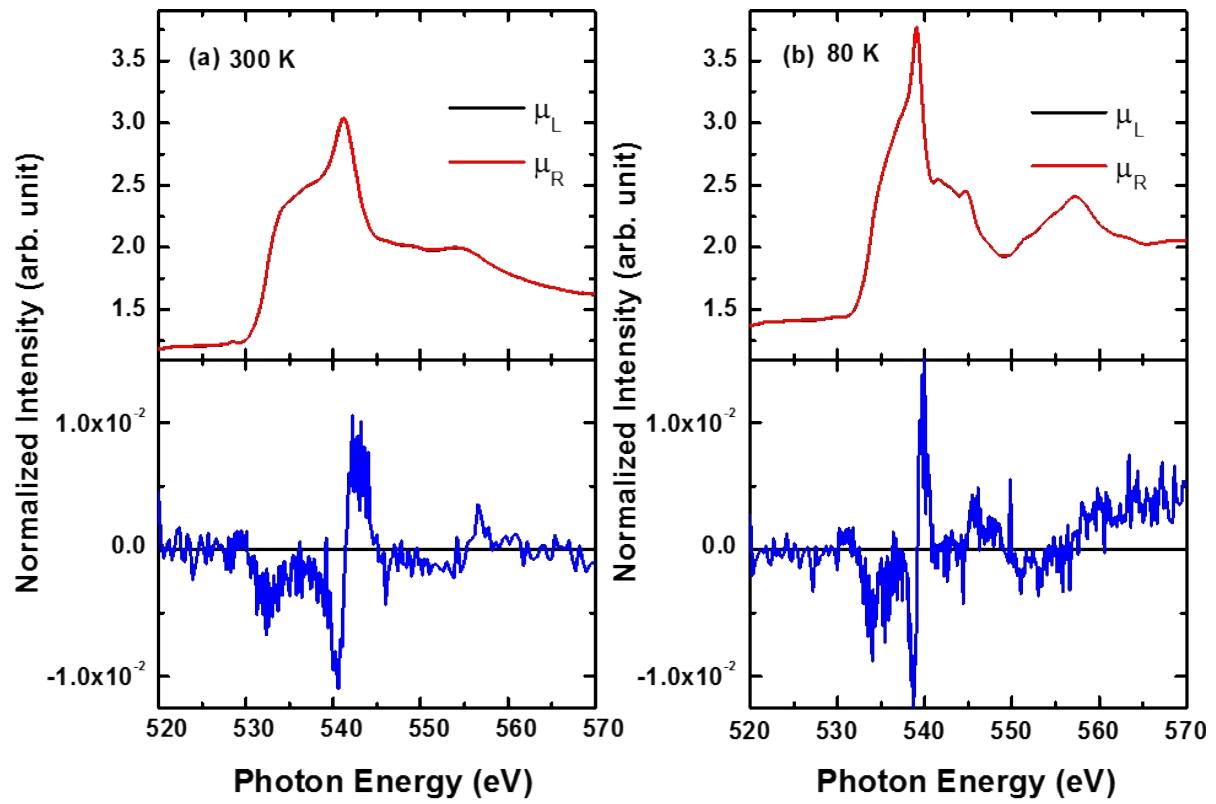


Figure S17: O K-edge NEXAFS spectra under different helicity of light (upper panel) and XMCD signal (lower panel) measured at (a) 300 K and (b) 80 K for non-implanted ZnO film.

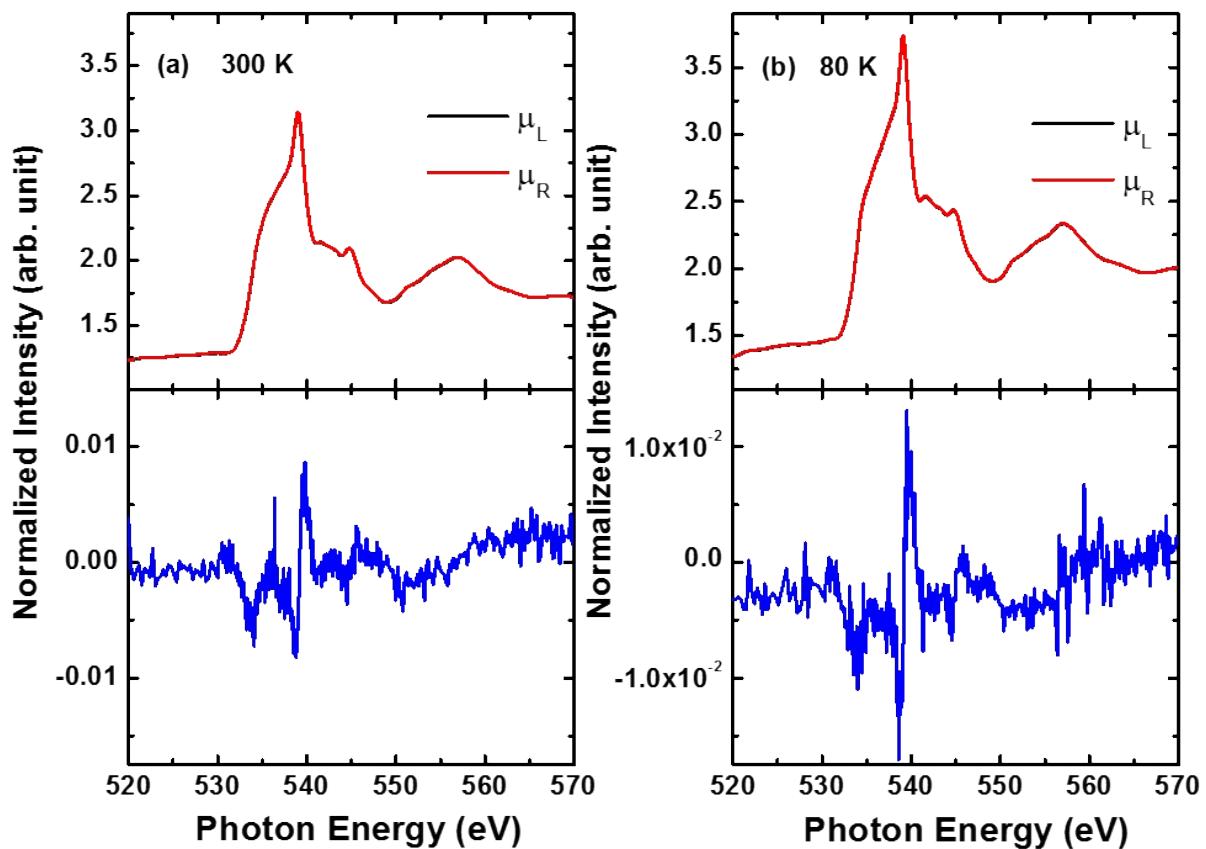


Figure S18: O K-edge NEXAFS spectra under different helicity of light (upper panel) and XMCD signal (lower panel) measured at (a) 300 K and (b) 80 K for Ar-implanted ZnO film.

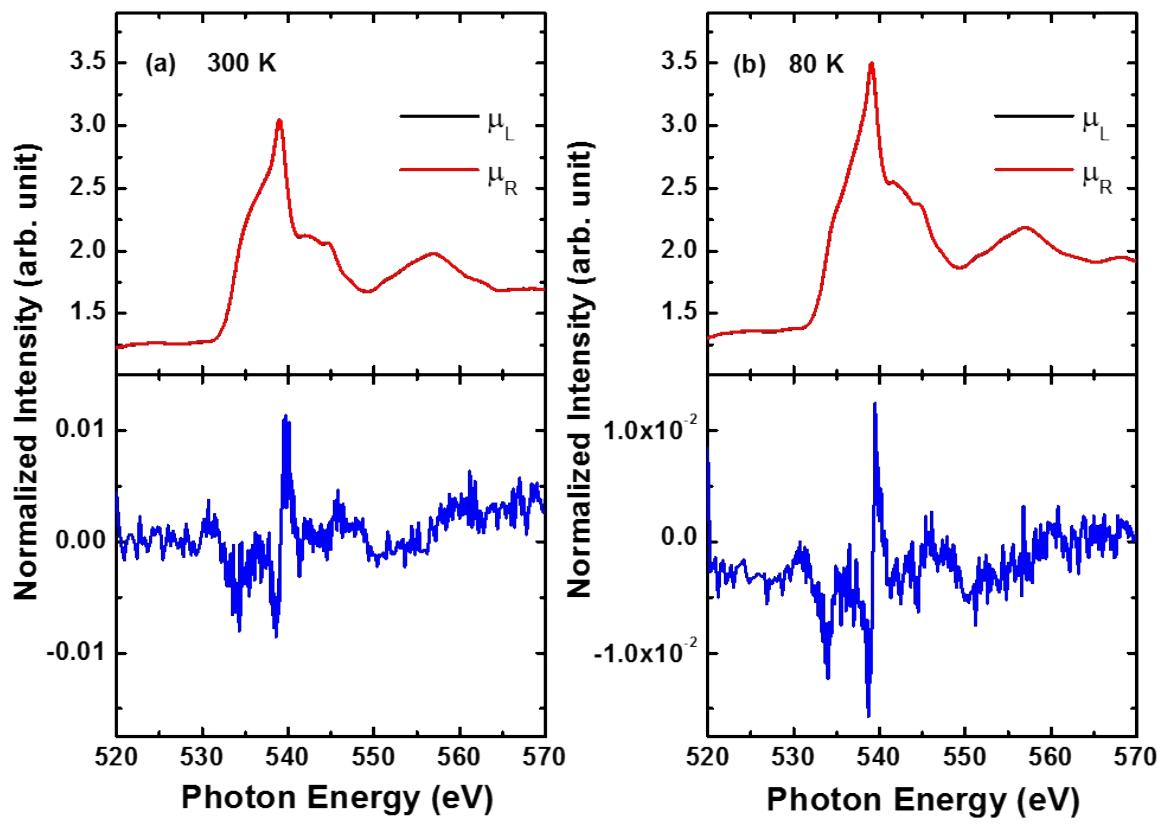


Figure S19: O K-edge NEXAFS spectra under different helicity of light (upper panel) and XMCD signal (lower panel) measured at (a) 300 K and (b) 80 K for Mn-implanted ZnO film.

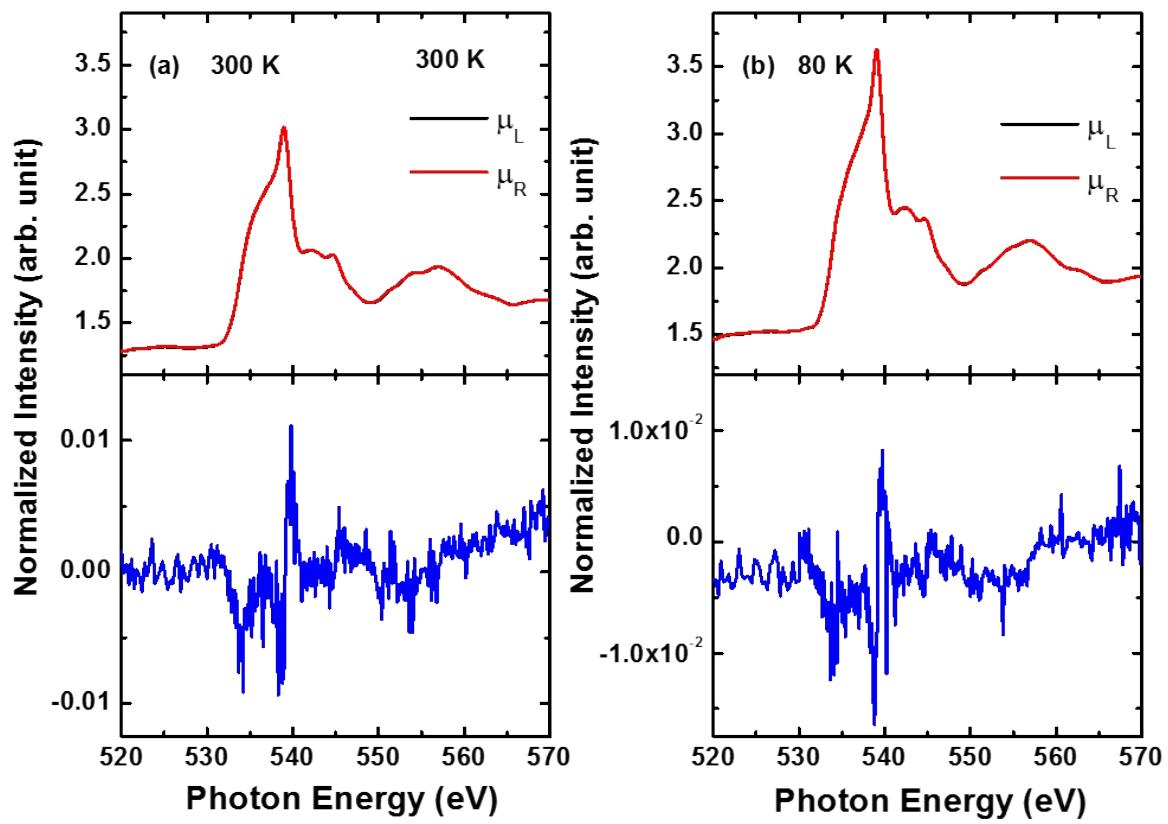


Figure S20: O K-edge NEXAFS spectra under different helicity of light (upper panel) and XMCD signal (lower panel) measured at (a) 300 K and (b) 80 K for Ag-implanted ZnO film.

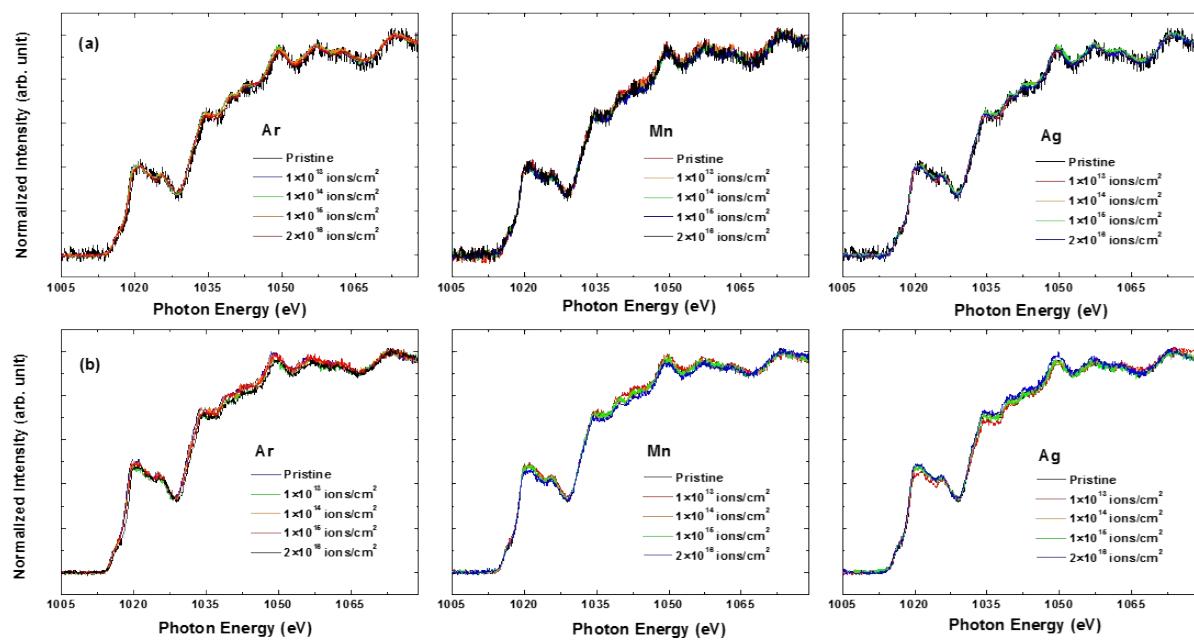


Figure S21: Zn L-edge (a) TEY mode and (b) TFY mode NEXAFS spectra for the implanted ZnO films at various doses.

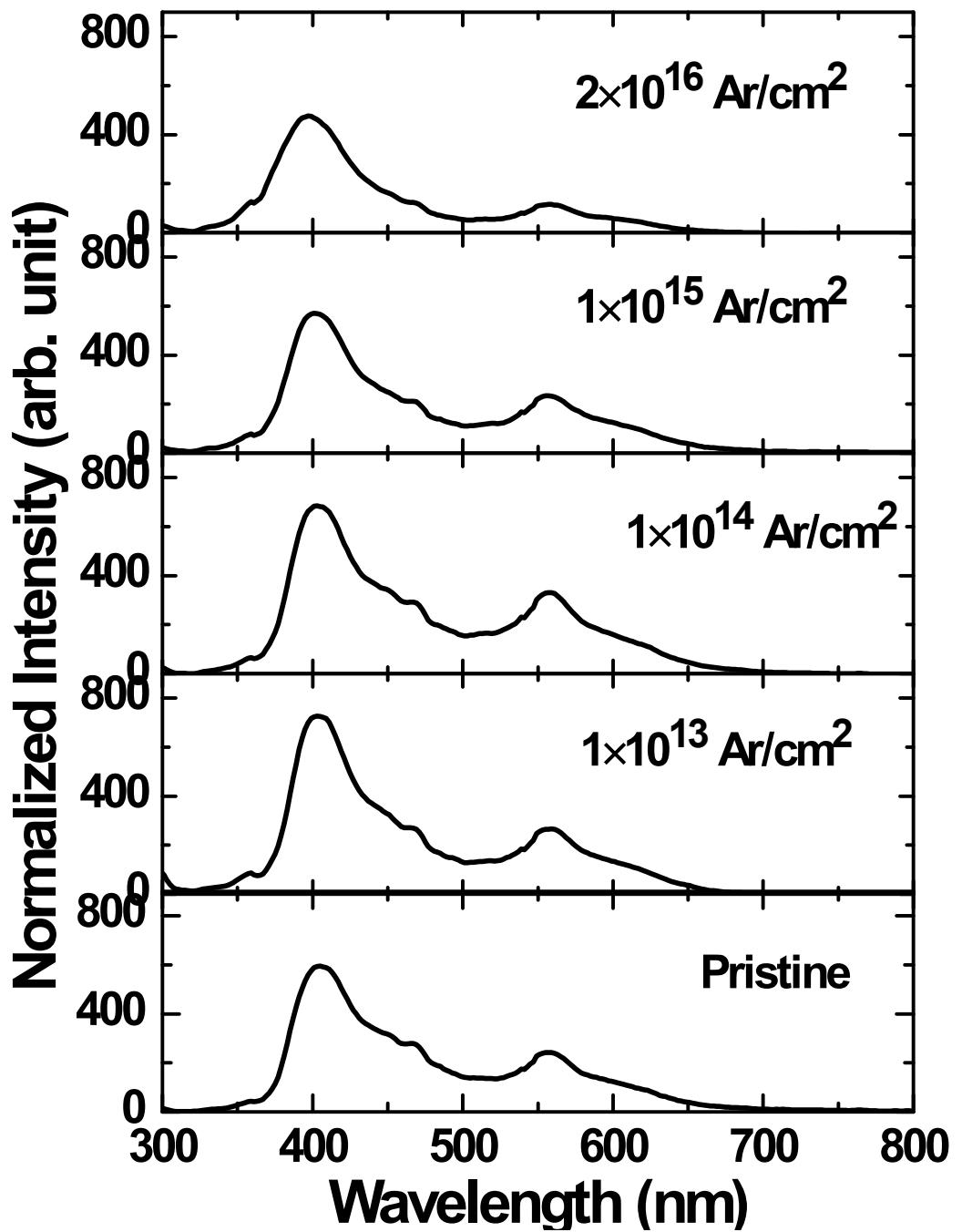


Figure S22: PL spectra of the Ar-implanted at various doses.

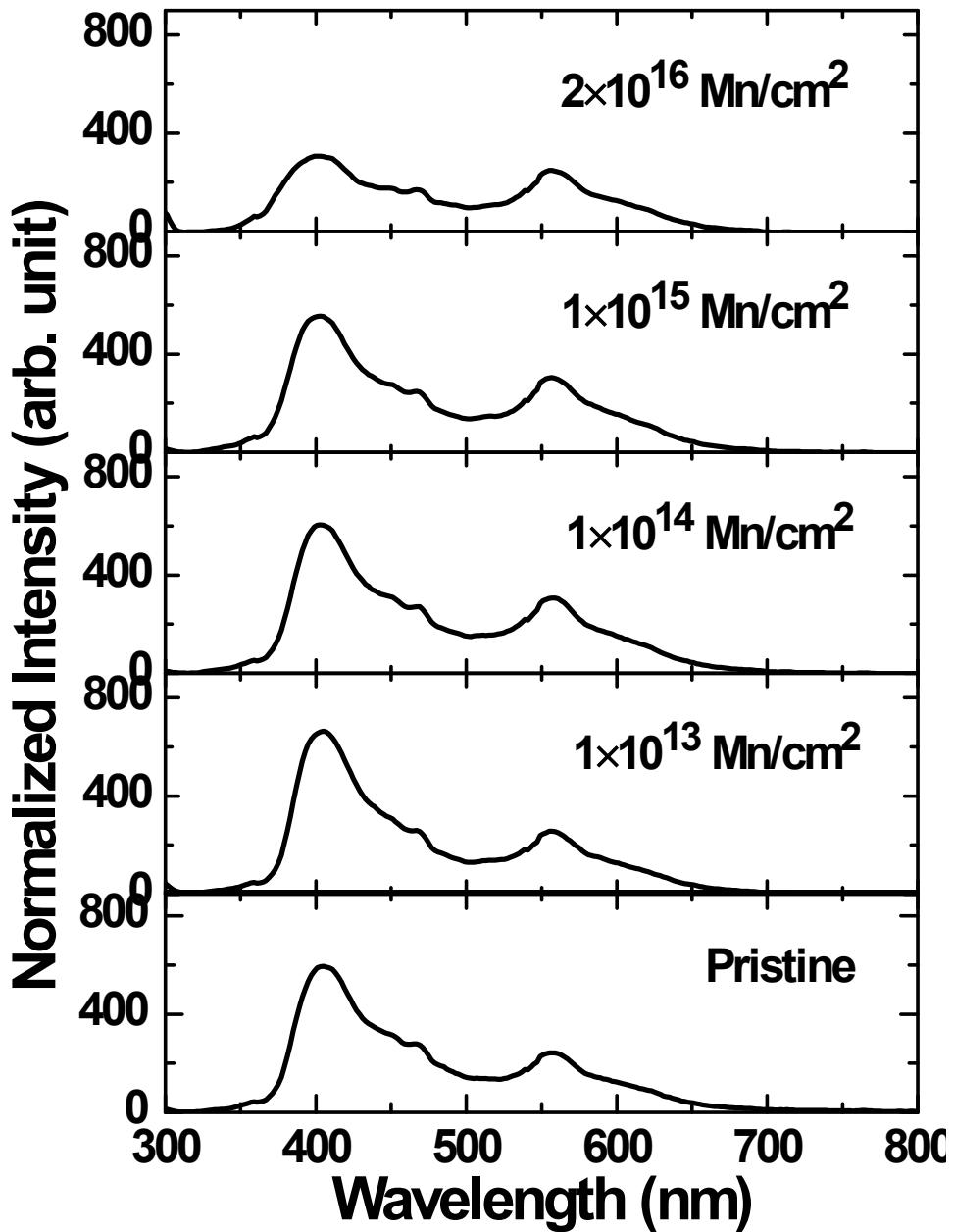


Figure S23: PL spectra of the Mn-implanted at various doses.

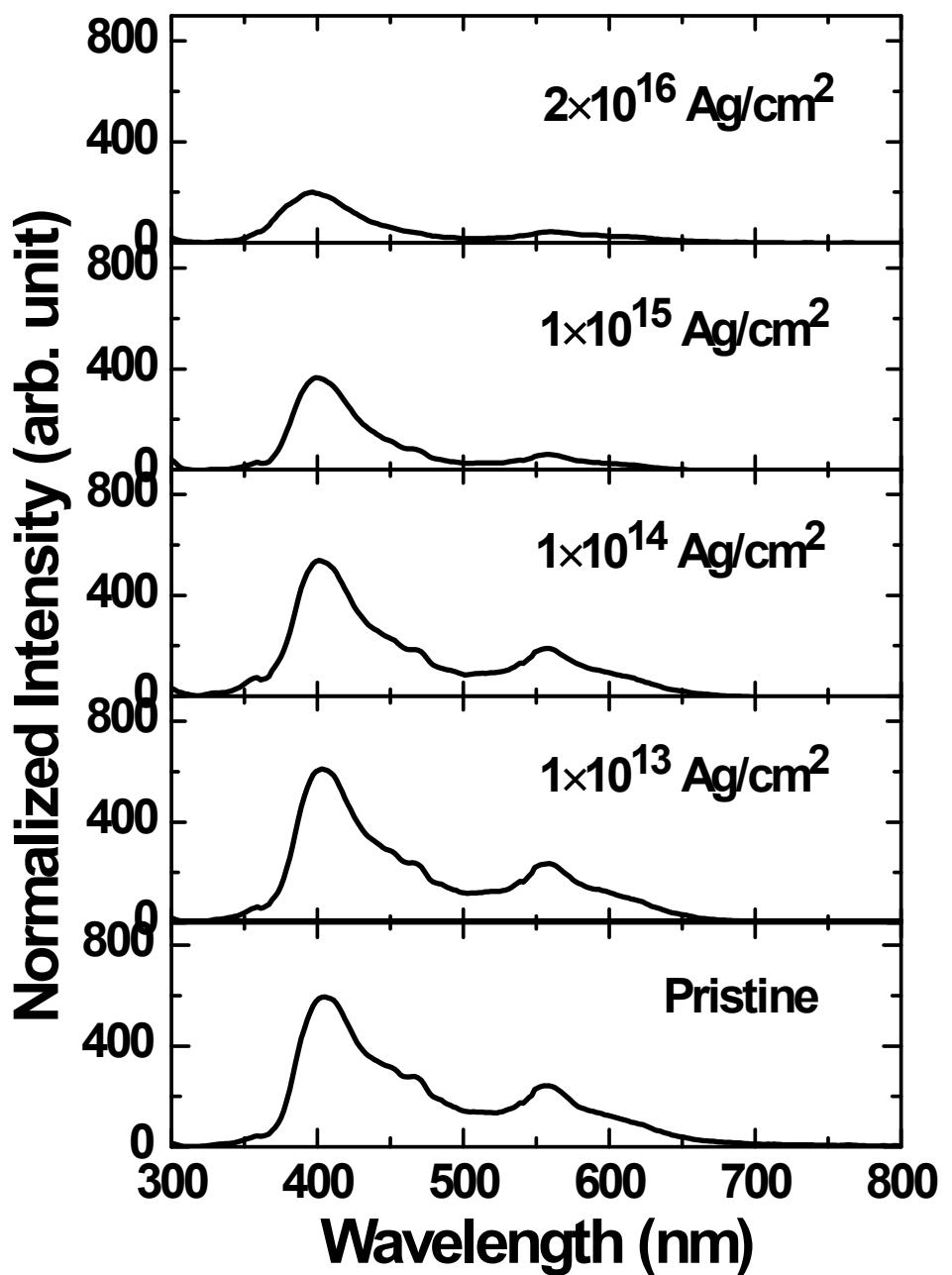


Figure S24: PL spectra of the Ag-implanted at various doses.

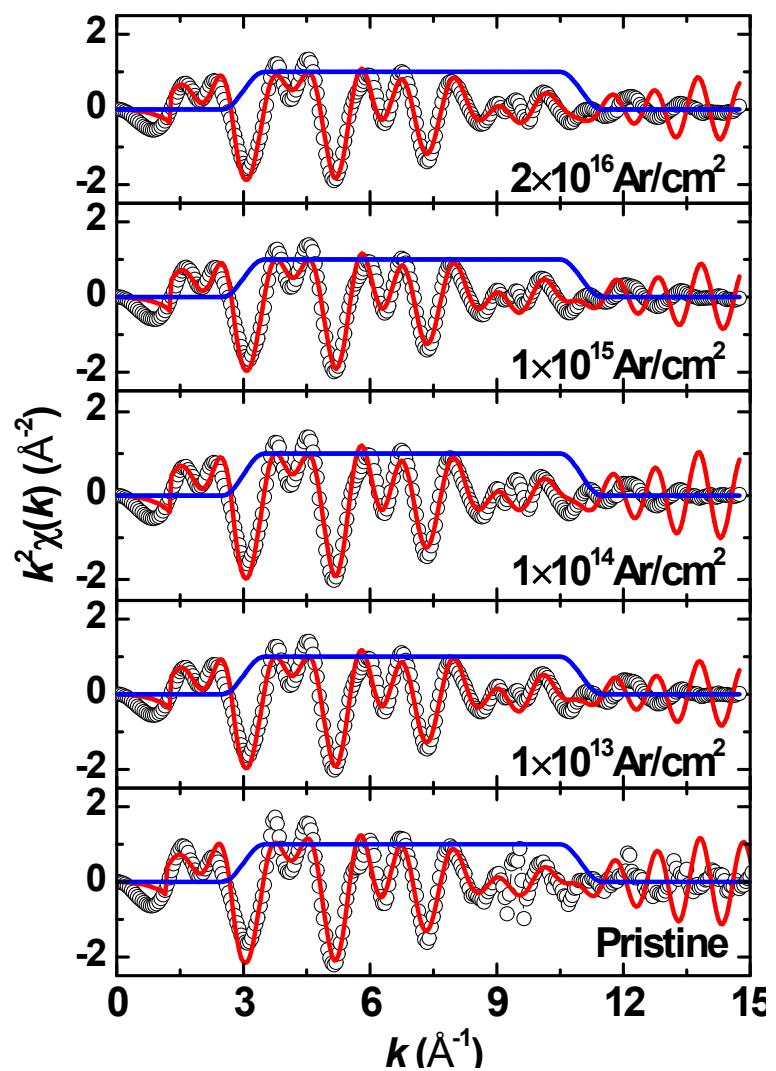


Figure 25: Simulated k -weight EXAFS spectra of Ar-implanted films at various doses.

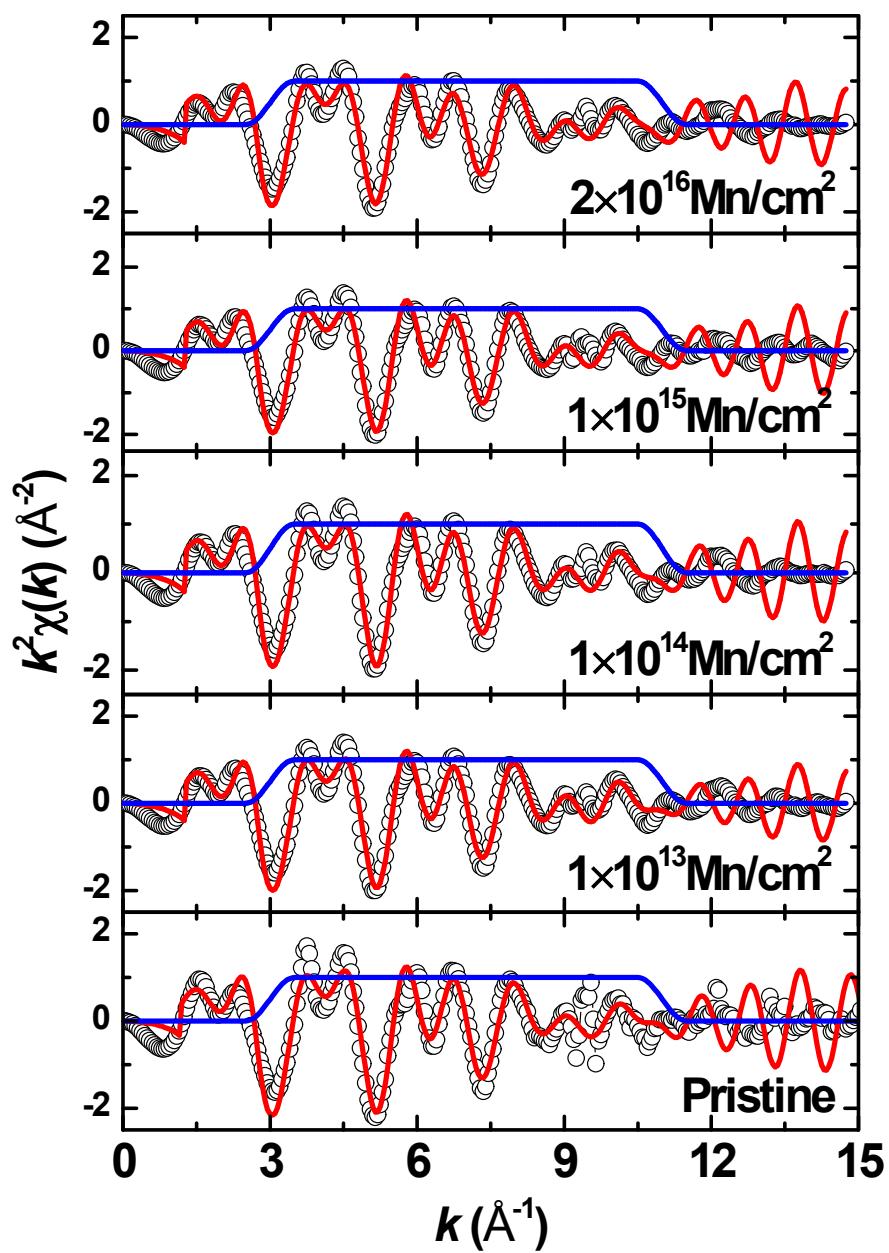


Figure 26: Simulated k -weight EXAFS spectra of Mn-implanted films at various doses.

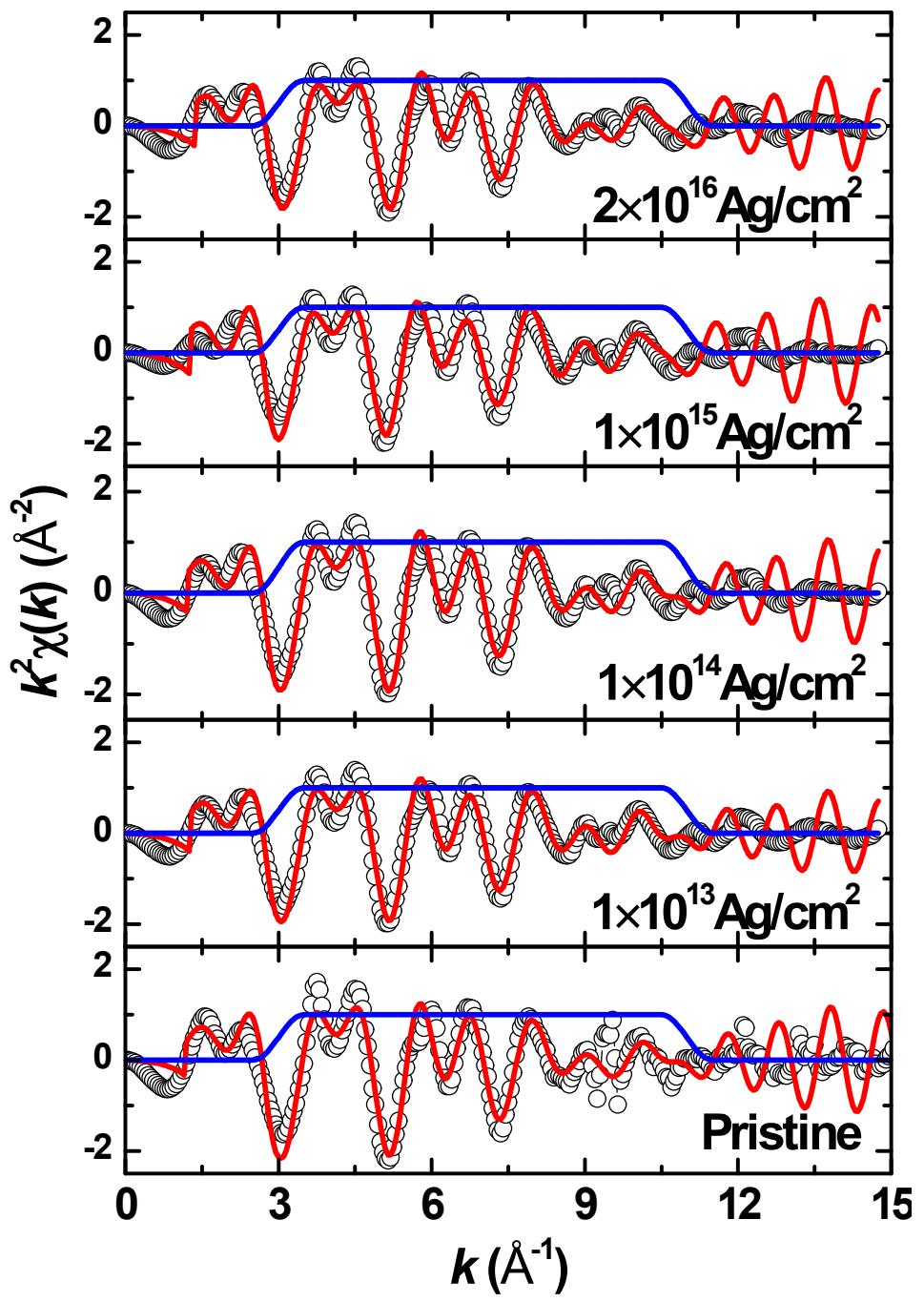


Figure 27: Simulated k -weight EXAFS spectra of Ag-implanted films at various doses.